

## Features

- Single 3.0V - 3.6V Supply
- Fast Read Access Time – 200 ns
- Automatic Page Write Operation
  - Internal Address and Data Latches for 64 Bytes
  - Internal Control Timer
- Fast Write Cycle Times
  - Page Write Cycle Time: 10 ms Maximum
  - 1- to 64-byte Page Write Operation
- Low Power Dissipation
  - 15 mA Active Current
  - 20  $\mu$ A CMOS Standby Current
- Hardware and Software Data Protection
- DATA Polling for End of Write Detection
- High Reliability CMOS Technology
  - Endurance: 10,000 Cycles
  - Data Retention: 10 Years
- JEDEC Approved Byte-wide Pinout
- Commercial and Industrial Temperature Ranges

## Description

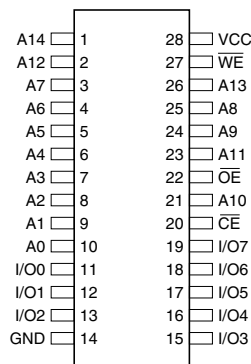
The AT28LV256 is a high-performance Electrically Erasable and Programmable Read Only Memory. Its 256K of memory is organized as 32,768 words by 8 bits. Manufactured with Atmel's advanced nonvolatile CMOS technology, the device offers access times to 200 ns with power dissipation of just 54 mW. When the device is deselected, the CMOS standby current is less than 200  $\mu$ A.

(continued)

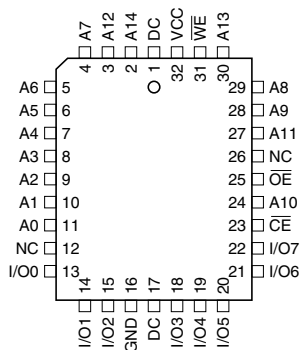
## Pin Configurations

Pin Name	Function
A0 - A14	Addresses
$\overline{CE}$	Chip Enable
$\overline{OE}$	Output Enable
$\overline{WE}$	Write Enable
I/O0 - I/O7	Data Inputs/Outputs
NC	No Connect
DC	Don't Connect

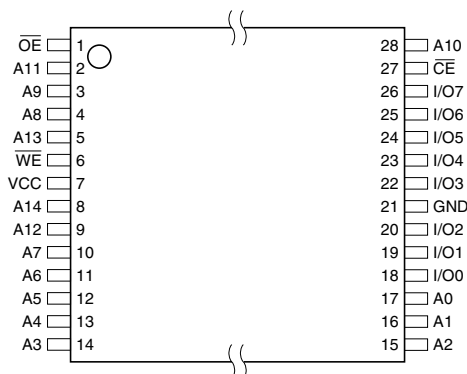
PDIP, SOIC  
Top View



PLCC  
Top View



TSOP  
Top View



Note: PLCC package pins 1 and 17 are DON'T CONNECT.



**256K (32K x 8)**  
**Low-Voltage™**  
**Parallel**  
**EEPROMs**

**AT28LV256**

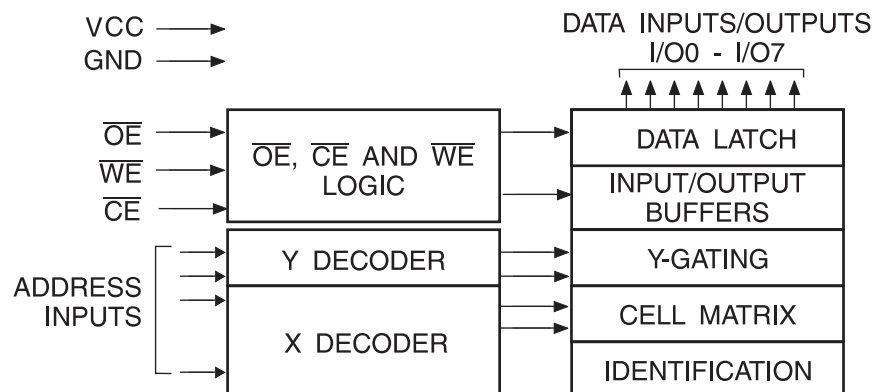


The AT28LV256 is accessed like a Static RAM for the read or write cycle without the need for external components. The device contains a 64-byte page register to allow writing of up to 64 bytes simultaneously. During a write cycle, the addresses and 1 to 64 bytes of data are internally latched, freeing the address and data bus for other operations. Following the initiation of a write cycle, the device will automatically write the latched data using an internal control timer. The end of a write cycle can be detected by DATA polling

of I/O7. Once the end of a write cycle has been detected a new access for a read or write can begin.

Atmel's 28LV256 has additional features to ensure high quality and manufacturability. The device utilizes internal error correction for extended endurance and improved data retention characteristics. An optional software data protection mechanism is available to guard against inadvertent writes. The device also includes an extra 64 bytes of EEPROM for device identification or tracking.

## Block Diagram



## Absolute Maximum Ratings\*

Temperature under Bias .....	-55°C to +125°C
Storage Temperature .....	-65°C to +150°C
All Input Voltages (including NC Pins) with Respect to Ground .....	-0.6V to +6.25V
All Output Voltages with Respect to Ground .....	-0.6V to $V_{CC} + 0.6V$
Voltage on $\overline{OE}$ and A9 with Respect to Ground .....	-0.6V to +13.5V

**\*NOTICE:** Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability

## Device Operation

**READ:** The AT28LV256 is accessed like a Static RAM. When  $\overline{CE}$  and  $\overline{OE}$  are low and  $\overline{WE}$  is high, the data stored at the memory location determined by the address pins is asserted on the outputs. The outputs are put in the high impedance state when either  $\overline{CE}$  or  $\overline{OE}$  is high. This dual-line control gives designers flexibility in preventing bus contention in their system.

**BYTE WRITE:** A low pulse on the  $\overline{WE}$  or  $\overline{CE}$  input with  $\overline{CE}$  or  $\overline{WE}$  low (respectively) and  $\overline{OE}$  high initiates a write cycle. The address is latched on the falling edge of  $\overline{CE}$  or  $\overline{WE}$ , whichever occurs last. The data is latched by the first rising edge of  $\overline{CE}$  or  $\overline{WE}$ . Once a byte write has been started it will automatically time itself to completion. Once a programming operation has been initiated and for the duration of  $t_{WC}$ , a read operation will effectively be a polling operation.

**PAGE WRITE:** The page write operation of the AT28LV256 allows 1 to 64 bytes of data to be written into the device during a single internal programming period. A page write operation is initiated in the same manner as a byte write; the first byte written can then be followed by 1 to 63 additional bytes. Each successive byte must be written within  $150\ \mu s$  ( $t_{BLC}$ ) of the previous byte. If the  $t_{BLC}$  limit is exceeded the AT28LV256 will cease accepting data and commence the internal programming operation. All bytes during a page write operation must reside on the same page as defined by the state of the A6 - A14 inputs. For each  $\overline{WE}$  high to low transition during the page write operation, A6 - A14 must be the same.

The A0 to A5 inputs are used to specify which bytes within the page are to be written. The bytes may be loaded in any order and may be altered within the same load period. Only bytes which are specified for writing will be written; unnecessary cycling of other bytes within the page does not occur.

**DATA POLLING:** The AT28LV256 features  $\overline{DATA}$  Polling to indicate the end of a write cycle. During a byte or page write cycle an attempted read of the last byte written will result in the complement of the written data to be presented on I/O7. Once the write cycle has been completed, true data is valid on all outputs, and the next write cycle may begin. DATA Polling may begin at anytime during the write cycle.

**TOGGLE BIT:** In addition to  $\overline{DATA}$  Polling the AT28LV256 provides another method for determining the end of a write cycle. During the write operation, successive attempts to

read data from the device will result in I/O6 toggling between one and zero. Once the write has completed, I/O6 will stop toggling and valid data will be read. Reading the toggle bit may begin at any time during the write cycle.

**DATA PROTECTION:** If precautions are not taken, inadvertent writes may occur during transitions of the host system power supply. Atmel has incorporated both hardware and software features that will protect the memory against inadvertent writes.

**HARDWARE PROTECTION:** Hardware features protect against inadvertent writes to the AT28LV256 in the following ways: (a)  $V_{CC}$  power-on delay—once  $V_{CC}$  has reached 1.8V (typical) the device will automatically time out 10 ms (typical) before allowing a write; (b) write inhibit—holding any one of  $\overline{OE}$  low,  $\overline{CE}$  high or  $\overline{WE}$  high inhibits write cycles; and (c) noise filter—pulses of less than 15 ns (typical) on the  $\overline{WE}$  or  $\overline{CE}$  inputs will not initiate a write cycle.

**SOFTWARE DATA PROTECTION:** A software-controlled data protection feature has been implemented on the AT28LV256. Software data protection (SDP) helps prevent inadvertent writes from corrupting the data in the device. SDP can prevent inadvertent writes during power-up and power-down as well as any other potential periods of system instability.

The AT28LV256 can only be written using the software data protection feature. A series of three write commands to specific addresses with specific data must be presented to the device before writing in the byte or page mode. The same three write commands must begin each write operation. All software write commands must obey the page mode write timing specifications. The data in the 3-byte command sequence is not written to the device; the address in the command sequence can be utilized just like any other location in the device.

Any attempt to write to the device without the 3-byte sequence will start the internal write timers. No data will be written to the device; however, for the duration of  $t_{WC}$ , read operations will effectively be polling operations.

**DEVICE IDENTIFICATION:** An extra 64 bytes of EEPROM memory are available to the user for device identification. By raising A9 to  $12V \pm 0.5V$  and using address locations 7FC0H to 7FFFH the additional bytes may be written to or read from in the same manner as the regular memory array.

## DC and AC Operating Range

		AT28LV256-20	AT28LV256-25
Operating Temperature (Case)	Com.	0°C - 70°C	0°C - 70°C
	Ind.	-40°C - 85°C	-40°C - 85°C
V <sub>CC</sub> Power Supply		3.0V - 3.6V	3.0V - 3.6V

## Operating Modes

Mode	$\overline{\text{CE}}$	$\overline{\text{OE}}$	$\overline{\text{WE}}$	I/O
Read	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	D <sub>OUT</sub>
Write <sup>(2)</sup>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	D <sub>IN</sub>
Standby/Write Inhibit	V <sub>IH</sub>	X <sup>(1)</sup>	X	High Z
Write Inhibit	X	X	V <sub>IH</sub>	
Write Inhibit	X	V <sub>IL</sub>	X	
Output Disable	X	V <sub>IH</sub>	X	High Z
Chip Erase	V <sub>IL</sub>	V <sub>H</sub> <sup>(3)</sup>	V <sub>IL</sub>	High Z

- Notes:
1. X can be V<sub>IL</sub> or V<sub>IH</sub>.
  2. Refer to AC programming waveforms.
  3. V<sub>H</sub> = 12.0V ± 0.5V.

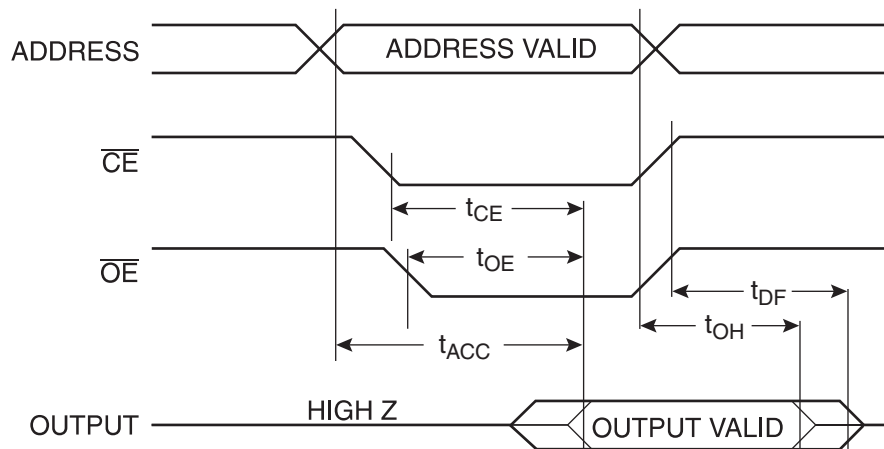
## DC Characteristics

Symbol	Parameter	Condition	Min	Max	Units
I <sub>LI</sub>	Input Load Current	V <sub>IN</sub> = 0V to V <sub>CC</sub> + 1V		10	μA
I <sub>LO</sub>	Output Leakage Current	V <sub>I/O</sub> = 0V to V <sub>CC</sub>		10	μA
I <sub>SB</sub>	V <sub>CC</sub> Standby Current CMOS	$\overline{\text{CE}} = V_{CC} - 0.3V$ to V <sub>CC</sub> + 1V	Com.	20	μA
			Ind.	50	μA
I <sub>CC</sub>	V <sub>CC</sub> Active Current	f = 5 MHz; I <sub>OUT</sub> = 0 mA		15	mA
V <sub>IL</sub>	Input Low Voltage			0.6	V
V <sub>IH</sub>	Input High Voltage		2.0		V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 1.6 mA		0.3	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -100 μA	2.0		V

## AC Read Characteristics

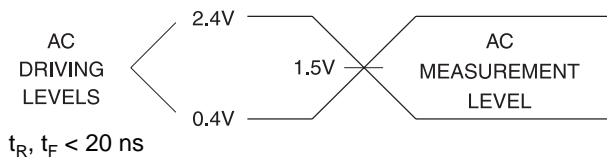
Symbol	Parameter	AT28LV256-20		AT28LV256-25		Units
		Min	Max	Min	Max	
$t_{ACC}$	Address to Output Delay		200		250	ns
$t_{CE}^{(1)}$	$\overline{CE}$ to Output Delay		200		250	ns
$t_{OE}^{(2)}$	$\overline{OE}$ to Output Delay	0	80	0	100	ns
$t_{DF}^{(3)(4)}$	$\overline{CE}$ or $\overline{OE}$ to Output Float	0	55	0	60	ns
$t_{OH}$	Output Hold from $\overline{OE}$ , $\overline{CE}$ or Address, whichever occurred first	0		0		ns

## AC Read Waveforms<sup>(1)(2)(3)(4)</sup>

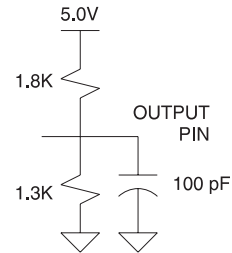


- Notes:
- $\overline{CE}$  may be delayed up to  $t_{ACC} - t_{CE}$  after the address transition without impact on  $t_{ACC}$ .
  - $\overline{OE}$  may be delayed up to  $t_{CE} - t_{OE}$  after the falling edge of  $\overline{CE}$  without impact on  $t_{CE}$  or by  $t_{ACC} - t_{OE}$  after an address change without impact on  $t_{ACC}$ .
  - $t_{DF}$  is specified from  $\overline{OE}$  or  $\overline{CE}$  whichever occurs first ( $C_L = 5$  pF).
  - This parameter is characterized and is not 100% tested.

## Input Test Waveforms and Measurement Level



## Output Test Load



## Pin Capacitance

$f = 1$  MHz,  $T = 25^\circ\text{C}^{(1)}$

Symbol	Typ	Max	Units	Conditions
$C_{IN}$	4	6	pF	$V_{IN} = 0V$
$C_{OUT}$	8	12	pF	$V_{OUT} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

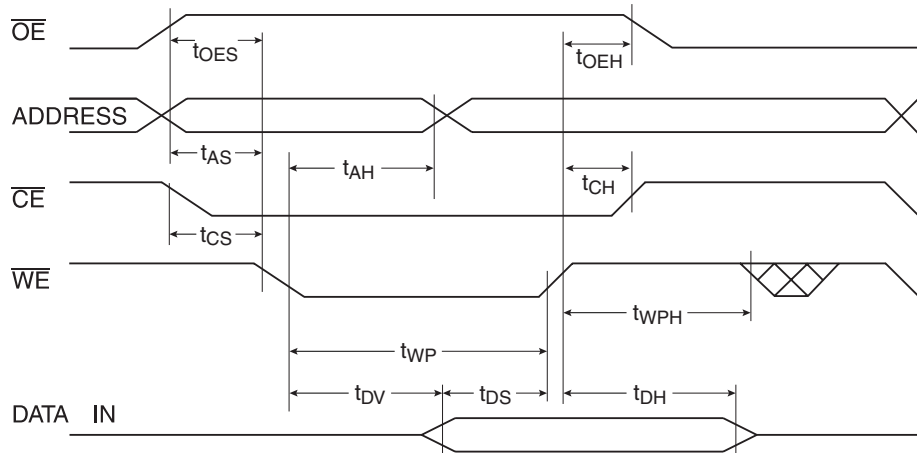
## AC Write Characteristics

Symbol	Parameter	Min	Max	Units
$t_{AS}, t_{OES}$	Address, $\overline{OE}$ Set-up Time	0		ns
$t_{AH}$	Address Hold Time	50		ns
$t_{CS}$	Chip Select Set-up Time	0		ns
$t_{CH}$	Chip Select Hold Time	0		ns
$t_{WP}$	Write Pulse Width ( $\overline{WE}$ or $\overline{CE}$ )	200		ns
$t_{DS}$	Data Set-up Time	50		ns
$t_{DH}, t_{OEH}$	Data, $\overline{OE}$ Hold Time	0		ns
$t_{DV}$	Time to Data Valid	NR <sup>(1)</sup>		

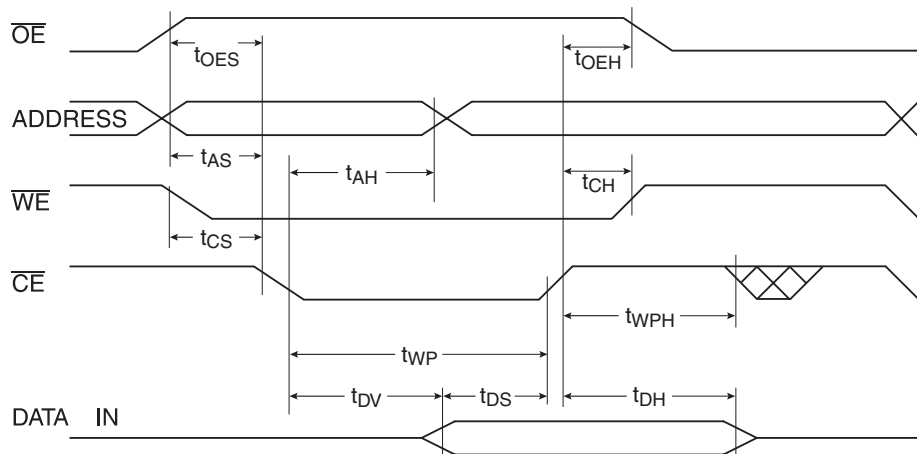
Note: 1. NR = No Restriction.

## AC Write Waveforms

### $\overline{WE}$ Controlled



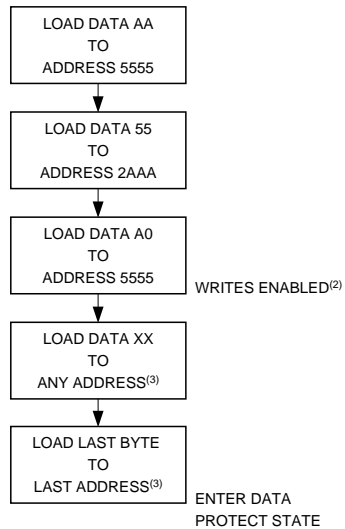
### $\overline{CE}$ Controlled



## Page Mode Characteristics

Symbol	Parameter	Min	Max	Units
$t_{WC}$	Write Cycle Time		10	ms
$t_{AS}$	Address Set-up Time	0		ns
$t_{AH}$	Address Hold Time	50		ns
$t_{DS}$	Data Set-up Time	50		ns
$t_{DH}$	Data Hold Time	0		ns
$t_{WPH}$	Write Pulse Width	200		ns
$t_{BLC}$	Byte Load Cycle Time		150	$\mu$ s
$t_{WPH}$	Write Pulse Width High	100		ns

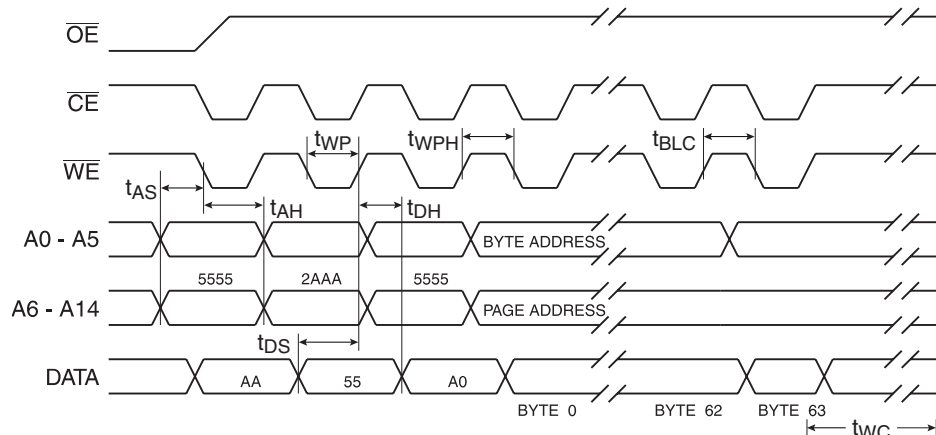
## Programming Algorithm



Notes for software program code:

1. Data Format: I/O7 - I/O0 (Hex); Address Format: A14 - A0 (Hex).
2. Data protect state will be re-activated at the end of program cycle.
3. 1 to 64 bytes of data are loaded.

## Software Protected Program Cycle Waveforms<sup>(1)(2)(3)</sup>



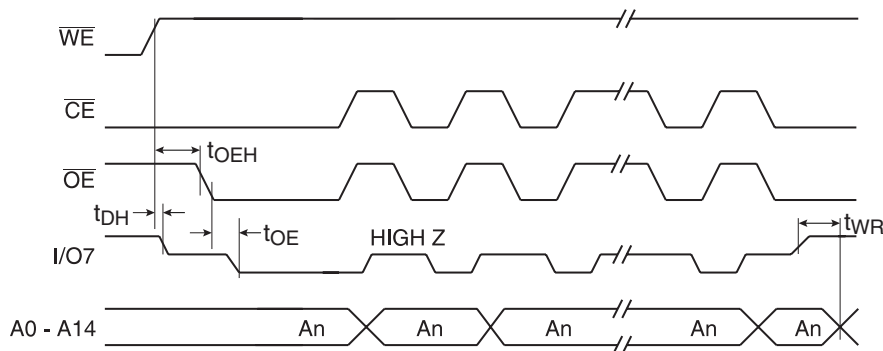
- Notes:
1. A0 - A14 must conform to the addressing sequence for the first three bytes as shown above.
  2. A6 through A14 must specify the same page address during each high to low transition of  $\overline{WE}$  (or  $\overline{CE}$ ) after the software code has been entered.
  3.  $\overline{OE}$  must be high only when  $\overline{WE}$  and  $\overline{CE}$  are both low.

## DATA Polling Characteristics<sup>(1)</sup>

Symbol	Parameter	Min	Typ	Max	Units
$t_{DH}$	Data Hold Time	0			ns
$t_{OE\overline{H}}$	$\overline{OE}$ Hold Time	0			ns
$t_{OE}$	$\overline{OE}$ to Output Delay <sup>(2)</sup>				ns
$t_{WR}$	Write Recovery Time	0			ns

Notes: 1. These parameters are characterized and not 100% tested.  
2. See “AC Read Characteristics” on page 5.

## DATA Polling Waveforms

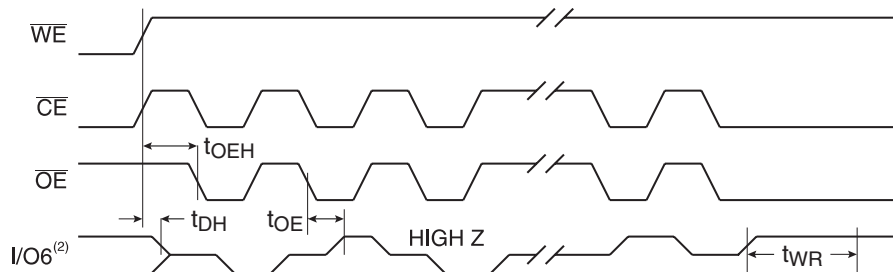


## Toggle Bit Characteristics<sup>(1)</sup>

Symbol	Parameter	Min	Typ	Max	Units
$t_{DH}$	Data Hold Time	10			ns
$t_{OE\overline{H}}$	$\overline{OE}$ Hold Time	10			ns
$t_{OE}$	$\overline{OE}$ to Output Delay <sup>(2)</sup>				ns
$t_{OEHP}$	$\overline{OE}$ High Pulse	150			ns
$t_{WR}$	Write Recovery Time	0			ns

Notes: 1. These parameters are characterized and not 100% tested.  
2. See “AC Read Characteristics” on page 5.

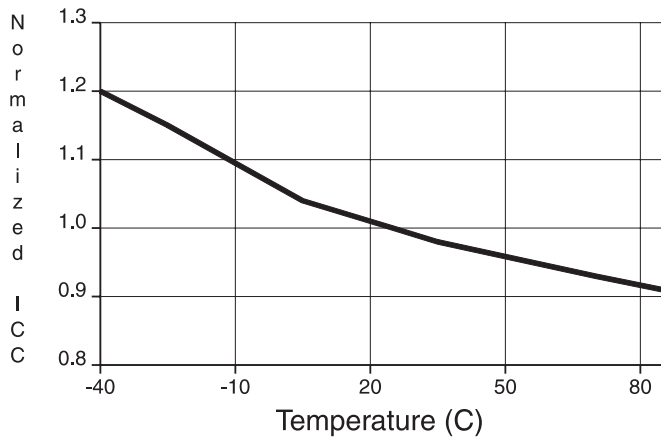
## Toggle Bit Waveforms



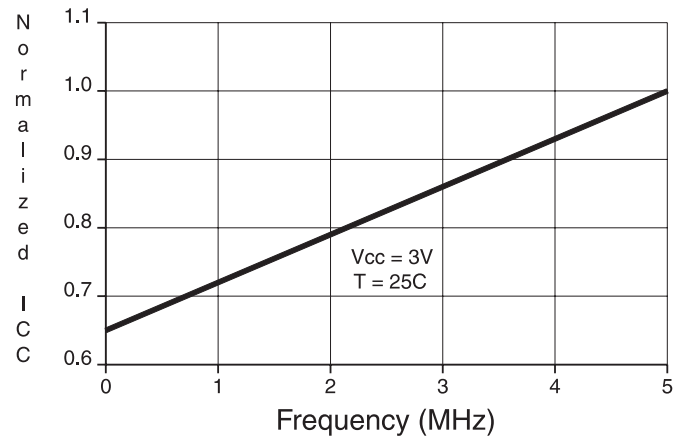
Notes: 1. Toggling either  $\overline{OE}$  or  $\overline{CE}$  or both  $\overline{OE}$  and  $\overline{CE}$  will operate toggle bit.  
2. Beginning and ending state of I/O6 will vary.  
3. Any address location may be used but the address should not vary.



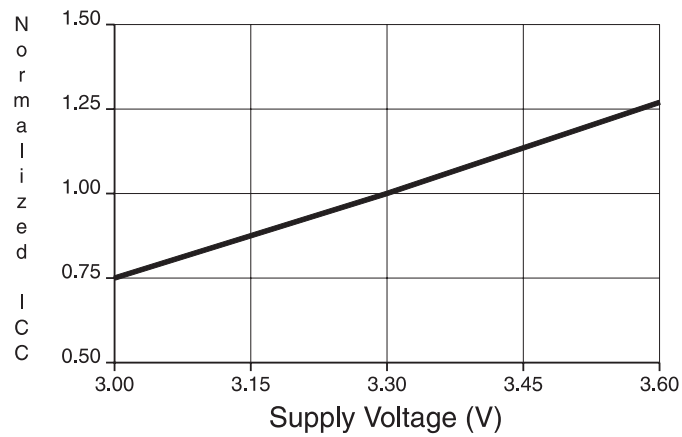
NORMALIZED SUPPLY CURRENT vs.  
TEMPERATURE



NORMALIZED SUPPLY CURRENT vs.  
ADDRESS FREQUENCY



NORMALIZED SUPPLY CURRENT vs.  
SUPPLY VOLTAGE





## Ordering Information<sup>(1)</sup>

t <sub>ACC</sub> (ns)	I <sub>CC</sub> (mA)		Ordering Code	Package	Operation Range
	Active	Standby			
200	15	0.02	AT28LV256-20JC	32J	Commercial (0° to 70°C)
			AT28LV256-20PC	28P6	
			AT28LV256-20SC	28S	
			AT28LV256-20TC	28T	
	15	0.02	AT28LV256-20JI	32J	Industrial (-40° to 85°C)
			AT28LV256-20PI	28P6	
			AT28LV256-20SI	28S	
			AT28LV256-20TI	28T	
250	15	0.02	AT28LV256-25JC	32J	Commercial (0° to 70°C)
			AT28LV256-25PC	28P6	
			AT28LV256-20SC	28S	
			AT28LV256-25TC	28T	
	15	0.02	AT28LV256-25JI	32J	Industrial (-40° to 85°C)
			AT28LV256-25PI	28P6	
			AT28LV256-20SI	28S	
			AT28LV256-25TI	28T	

Note: 1. See Valid Part Numbers table below.

## Valid Part Numbers

The following table lists standard Atmel products that can be ordered.

Device Numbers	Speed	Package and Temperature Combinations
AT28LV256	20	JC, JI, PC, PI, SC, SI, TC, TI
AT28LV256	25	JC, JI, PC, PI, SC, SI, TC, TI

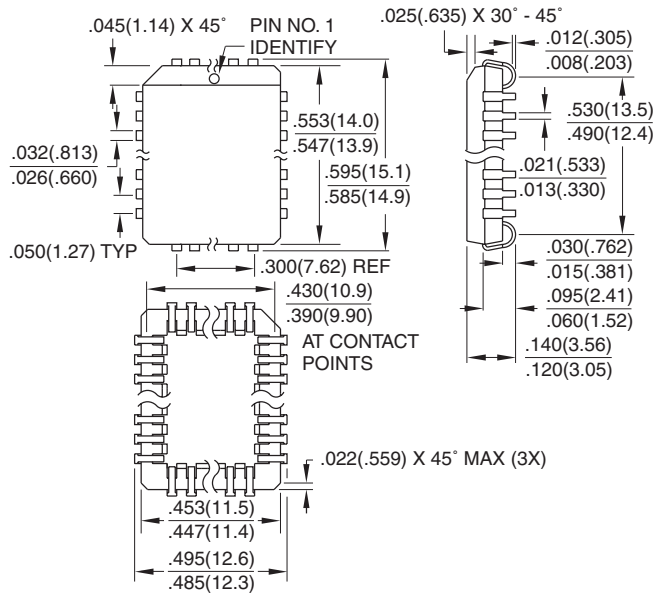
## Die Products

Reference Section: Parallel EEPROM Die Products

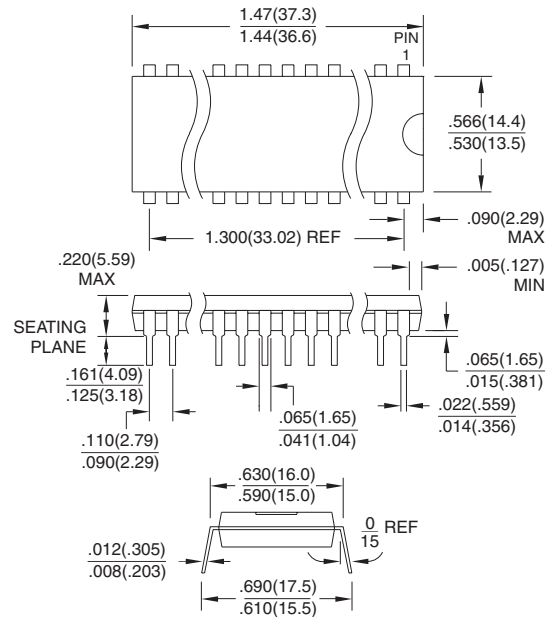
Package Type	
32J	32-lead, Plastic J-leaded Chip Carrier (PLCC)
28P6	28-lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)
28S	28-lead, 0.300" Wide, Plastic Gull Wing Small Outline (SOIC)
28T	28-lead, Plastic Thin Small Outline Package (TSOP)

## Packaging Information

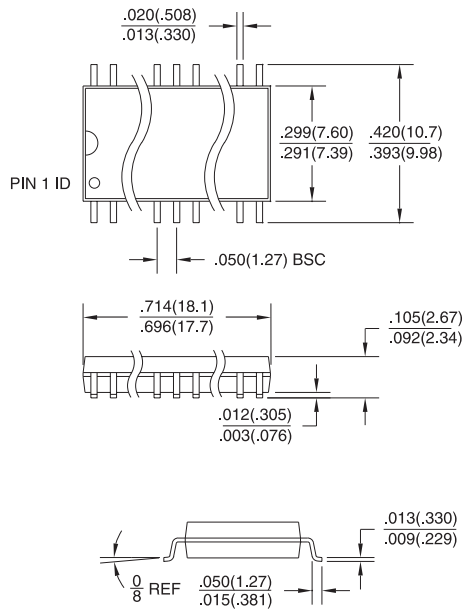
**32J**, 32-lead, Plastic J-leaded Chip Carrier (PLCC)  
Dimensions in Inches and (Millimeters)  
JEDEC STANDARD MS-016 AE



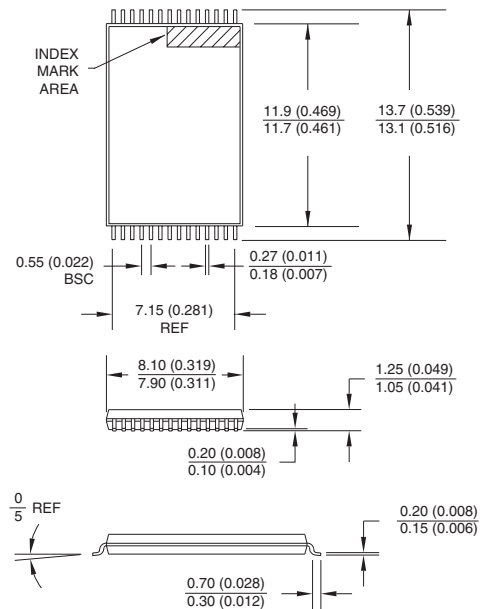
**28P6**, 28-lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)  
Dimensions in Inches and (Millimeters)  
JEDEC STANDARD MS-011 AB



**28S**, 28-lead, 0.300" Wide, Plastic Gull Wing Small Outline (SOIC)  
Dimensions in Inches and (Millimeters)



**28T**, 28-lead, Plastic Thin Small Outline Package (TSOP)  
Dimensions in Millimeters and (Inches)\*





## Atmel Headquarters

### *Corporate Headquarters*

2325 Orchard Parkway  
San Jose, CA 95131  
TEL (408) 441-0311  
FAX (408) 487-2600

### *Europe*

Atmel SarL  
Route des Arsenaux 41  
Casa Postale 80  
CH-1705 Fribourg  
Switzerland  
TEL (41) 26-426-5555  
FAX (41) 26-426-5500

### *Asia*

Atmel Asia, Ltd.  
Room 1219  
Chinachem Golden Plaza  
77 Mody Road Tsimhatsui  
East Kowloon  
Hong Kong  
TEL (852) 2721-9778  
FAX (852) 2722-1369

### *Japan*

Atmel Japan K.K.  
9F, Tonetsu Shinkawa Bldg.  
1-24-8 Shinkawa  
Chuo-ku, Tokyo 104-0033  
Japan  
TEL (81) 3-3523-3551  
FAX (81) 3-3523-7581

## Atmel Operations

### *Atmel Colorado Springs*

1150 E. Cheyenne Mtn. Blvd.  
Colorado Springs, CO 80906  
TEL (719) 576-3300  
FAX (719) 540-1759

### *Atmel Rousset*

Zone Industrielle  
13106 Rousset Cedex  
France  
TEL (33) 4-4253-6000  
FAX (33) 4-4253-6001

### *Atmel Smart Card ICs*

Scottish Enterprise Technology Park  
East Kilbride, Scotland G75 0QR  
TEL (44) 1355-357-000  
FAX (44) 1355-242-743

### *Atmel Grenoble*

Avenue de Rochepleine  
BP 123  
38521 Saint-Egreve Cedex  
France  
TEL (33) 4-7658-3000  
FAX (33) 4-7658-3480

---

### *Fax-on-Demand*

North America:  
1-(800) 292-8635  
International:  
1-(408) 441-0732

### *e-mail*

[literature@atmel.com](mailto:literature@atmel.com)

### *Web Site*

<http://www.atmel.com>

### *BBS*

1-(408) 436-4309

### © Atmel Corporation 2001.

Atmel Corporation makes no warranty for the use of its products, other than those expressly contained in the Company's standard warranty which is detailed in Atmel's Terms and Conditions located on the Company's web site. The Company assumes no responsibility for any errors which may appear in this document, reserves the right to change devices or specifications detailed herein at any time without notice, and does not make any commitment to update the information contained herein. No licenses to patents or other intellectual property of Atmel are granted by the Company in connection with the sale of Atmel products, expressly or by implication. Atmel's products are not authorized for use as critical components in life support devices or systems.

Marks bearing ® and/or ™ are registered trademarks and trademarks of Atmel Corporation.

Terms and product names in this document may be trademarks of others.



Printed on recycled paper.

2400AX-04/23/01/xM